## 90W, 28V High Power RF LDMOS FETs

### Description

The MA1509 is a 90-watt, highly rugged, unmatched LDMOS FET, designed for wideband commercial and industrial applications at frequencies HF to 1.5 GHz. It can be used in Class AB/B and Class C for all typical modulation formats.

•Typical Performance (On Innogration fixture with device soldered):

MA1509



	MA1509 Vds=28V Vgs=3.02V Idq=200mA CW							
Freq(MHz)	Pout(dBm)	Pout(W)	IDS(A)	Pin(dBm)	Gain(dB)	Eff(%)	2nd(dBc)	3rd(dBc)
30	50.45	110.92	6.79	30.6	19.85	58.34	-20.4	-10.4
50	50.58	114.29	6.81	31.4	19.18	59.94	-24.1	-10.0
70	50.82	120.78	6.65	31.2	19.62	64.87	-27.5	-9.1
90	50.71	117.76	6.27	31.6	19.11	67.08	-29.9	-7.9
108	50.86	121.90	6.25	31.3	19.56	69.66	-31.3	-7.7

### Features

- High Efficiency and Linear Gain Operations
- Integrated ESD Protection
- Excellent thermal stability, low HCI drift

### **Suitable Applications**

- 2-30MHz (HF or Short wave communication)
- 30-88MHz (Ground communication)
- 54-88MHz (TV VHF I)
- 88-108MHz (FM)
- 118 -140MHz (Avionics)

- Large Positive and Negative Gate/Source Voltage Range for Improved Class C Operation
- Pb-free, RoHS-compliant
- 136-174MHz (Commercial ground communication)
- 160-230MHz (TV VHF III)
- 30-512MHz (Jammer, Ground/Air communication)
- 470-860MHz (TV UHF)
- 100kHz 1000MHz (ISM, instrumentation)

#### Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
DrainSource Voltage	V <sub>DSS</sub>	+95	Vdc
GateSource Voltage	V <sub>GS</sub>	-10 to +10	Vdc
Operating Voltage	V <sub>dd</sub>	+40	Vdc
Storage Temperature Range	Tstg	-65 to +150	°C
Case Operating Temperature	Tc	+150	°C
Operating Junction Temperature	T٦	+225	°C

#### **Table 2. Thermal Characteristics**

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case	Duis	0.7	2044
$T_c$ = 85°C, $T_J$ =200°C, DC test	Rejc	0.7	°C/W

Test Methodology		Class				
Human Body Model (per JESD22A114)		Class 2				
Table 4. Electrical Characteristics (T_A = 25 $^\circ\!\!\!{\rm C}$ unless of	therwise noted)					
Characteristic	Symbol	Min	Тур	Max	Unit	
C Characteristics (per half section)						
Drain-Source Voltage		95			V	
V <sub>GS</sub> =0, I <sub>DS</sub> =1.0mA	V <sub>(BR)DSS</sub>					
Zero Gate Voltage Drain Leakage Current				1	μΑ	
(V <sub>DS</sub> = 28 V, V <sub>GS</sub> = 0 V)	I <sub>DSS</sub>					
GateSource Leakage Current						
(V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 0 V)	I <sub>GSS</sub>			1	μA	
Gate Threshold Voltage	M (u)		0.17		V	
(V <sub>DS</sub> = 28V, I <sub>D</sub> = 150 μA)	V <sub>GS</sub> (th)		2.17		v	
Gate Quiescent Voltage	N		3.3		v	
( $V_{DD}$ = 28 V, $I_D$ =500 mA, Measured in Functional Test)	V <sub>GS(Q)</sub>					
Common Source Input Capacitance			54		۳E	
(V <sub>GS</sub> = 0V, V <sub>DS</sub> =28 V, f = 1 MHz)	C <sub>ISS</sub>		54		pF	
Common Source Output Capacitance	Coss		18		pF	
(V <sub>GS</sub> = 0V, V <sub>DS</sub> =28 V, f = 1 MHz)	Coss				þ	
Common Source Feedback Capacitance			1.2		pF	
(V <sub>GS</sub> = 0V, V <sub>DS</sub> =28 V, f = 1 MHz)	C <sub>RSS</sub>	ORSS			P'	
unctional Tests (In Demo Test Fixture, 50 ohm system) $V_{DD}$	= 28 Vdc, I <sub>DQ</sub> = 500 mA,	f = 1000 MHz,	CW Signal M	easurements.		
Power Gain	Gp		18		dB	
Drain Efficiency@P1dB	η₀		60		%	
1 dB Compression Point	P <sub>-1dB</sub>		90		W	
Input Return Loss	IRL		-7		dB	
Drain Efficiency@P1dB 1 dB Compression Point Input Return Loss .coad Mismatch (In Innogration Test Fixture, 50 ohm syster	η <sub>0</sub> P <sub>-1dB</sub> IRL		500 mA, f = 10	60 90 -7	60 90 -7	
W Output Power	No Device [					

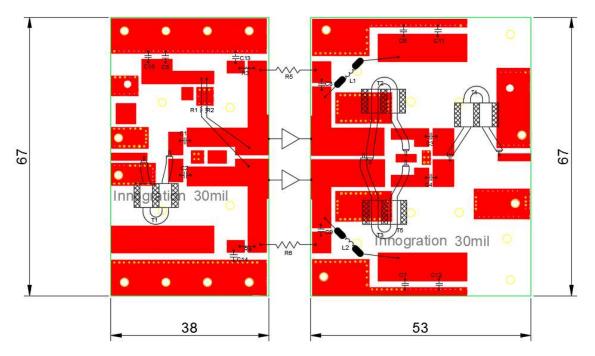
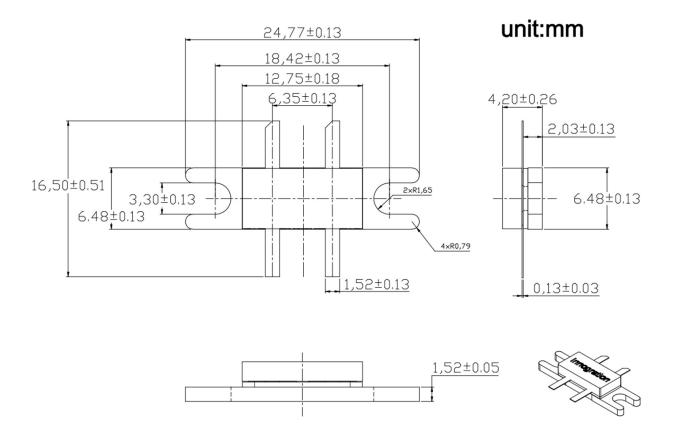


Figure 2. Test Circuit Component Layout

Table 5. Test Circuit Component Designations and Values

Part	description	Model
C1~C4	560pF	MQ101111
C5~C9	1000pF	MQ101111
C10~C12	10uF	Ceramic multilayer capacitor
C13, C14	10nF	Ceramic multilayer capacitor
R1,R2	<b>220</b> Ω	Pulg-in Resistor
R3,R4	<b>300</b> Ω	Chip Resistor
R5,R6	500 Ω	Pulg-in Resistor
L1,L2	d=1.5mm,D=4.2mm,13 turns	DIY
T1,T4	Foolar Zomm	BN-61-202
	50ohm 70mm	RFSFBU-086-50
Т2,Т3	25ohm 70mm	BN-61-202
	2301117011111	SFF-25-1.5

### Package Outline



### **Revision history**

#### Table 5. Document revision history

Date	Revision	Datasheet Status
2024/3/28	Rev 1.0	Preliminary Datasheet

Application data based on HL-24-12

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